



RADIO TEST REPORT

Test Report No. : 10105410H-B

Applicant : **Hosiden Corporation**
Type of Equipment : **Bluetooth module**
Model No. : **ARC0557**
FCC ID : **VIYARC0557**
Test regulation : **FCC Part 15 Subpart C: 2013**
Test Result : **Complied**

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2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

Date of test: November 19 and 23, 2013

Representative test engineer: T. Shimada
Takumi Shimada
Engineer of WiSE Japan,
UL Verification Service

Approved by: Masanori Nishiyama
Masanori Nishiyama
Manager of WiSE Japan,
UL Verification Service



NVLAP LAB CODE: 200572-0

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13-EM-F0429

CONTENTS	PAGE
SECTION 1: Customer information.....	4
SECTION 2: Equipment under test (E.U.T.).....	4
SECTION 3: Test specification, procedures & results.....	5
SECTION 4: Operation of E.U.T. during testing.....	8
SECTION 5: Radiated Spurious Emission	10
SECTION 6: Antenna Terminal Conducted Tests.....	11
APPENDIX 1: Data of EMI test.....	12
20dB Bandwidth and Carrier Frequency Separation.....	12
Number of Hopping Frequency	14
Dwell time.....	16
Maximum Peak Output Power.....	18
Radiated Spurious Emission	19
Conducted Spurious Emission	22
Conducted Emission Band Edge compliance	28
99%Occupied Bandwidth	29
APPENDIX 2: Test instruments	31
APPENDIX 3: Photographs of test setup.....	32
Radiated Spurious Emission	32
Worst Case Position (Horizontal: X-axis/ Vertical:Z-axis)	33

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SECTION 1: Customer information

Company Name : Hosiden Corporation
Address : 1-4-33, Kitakyuhoji, Yao, Osaka, 5810071, Japan
Telephone Number : +81-72-924-1195
Facsimile Number : +81-72-993-0724
Contact Person : Keiji Mine

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Bluetooth module
Model No. : ARC0557
Serial No. : Refer to Section 4, Clause 4.2
Rating : DC 2.0 to DC 3.0V
Receipt Date of Sample : November 14, 2013
Country of Mass-production : China
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product Description

General Specification

Clock frequency(ies) in the system : 16MHz

Radio Specification

[Bluetooth (Ver. 3.0 without EDR function)]

Radio Type : Transceiver
Frequency of Operation : 2402-2480MHz
Modulation : FHSS, GFSK
Power Supply (radio part input) : DC 1.8V
Antenna type : $\lambda/4$ meander antenna (printed on the PWB)
Antenna Gain : -3.0 dBi max

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SECTION 3: Test specification, procedures & results

3.1 Test Specification

Test Specification : FCC Part 15 Subpart C: 2013, final revised on September 30, 2013 and effective October 30, 2013

Title : FCC 47CFR Part15 Radio Frequency Device Subpart C Intentional Radiators
Section 15.207 Conducted limits
Section 15.247 Operation within the bands 902-928MHz,
2400-2483.5MHz, and 5725-5850MHz

* The EUT complies with FCC Part 15 Subpart B: 2013, final revised on September 30, 2013 and effective October 30, 2013.

3.2 Procedures and results

Item	Test Procedure	Specification	Worst Margin	Results	Remarks
Conducted Emission	FCC: ANSI C63.4:2003 7. AC powerline conducted emission measurements IC: RSS-Gen 7.2.4	FCC: Section 15.207 ----- IC: RSS-Gen 7.2.4	N/A *1)	N/A	-
Carrier Frequency Separation	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1) ----- IC: RSS-210 A8.1 (b)	See data.	Complied	Conducted
20dB Bandwidth	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1) ----- IC: RSS-210 A8.1 (a)		Complied	Conducted
Number of Hopping Frequency	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1)(iii) ----- IC: RSS-210 A8.1 (d)		Complied	Conducted
Dwell time	FCC: FCC Public Notice DA 00-705 IC: -	FCC: Section15.247(a)(1)(iii) ----- IC: RSS-210 A8.1 (d)		Complied	Conducted
Maximum Peak Output Power	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 4.8	FCC: Section15.247(a)(b)(1) ----- IC: RSS-210 A8.4 (2)		Complied	Conducted
Spurious Emission & Band Edge Compliance	FCC: FCC Public Notice DA 00-705 IC: RSS-Gen 4.9	FCC: Section15.247(d) ----- IC: RSS-210 A8.5 RSS-Gen 6 and 7.2.3		10.6dB 2354.011MHz, AV, Vert.	Complied

Note: UL Japan, Inc.'s EMI Work Procedures No. 13-EM-W0420 and 13-EM-W0422.

*1) The test is not applicable since the EUT is not the device that is designed to be connected to the public utility (AC) power line.

* In case any questions arise about test procedure, ANSI C63.4: 2003 is also referred.

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FCC 15.31 (e)

This EUT provides stable voltage (DC1.8V) constantly to RF Module regardless of input voltage. Therefore, this EUT complies with the requirement.

FCC Part 15.203/212 Antenna requirement

It is impossible for end users to replace the antenna, because the antenna is mounted inside of the EUT. Therefore, the equipment complies with the antenna requirement of Section 15.203.

3.3 Addition to standard

Item	Test Procedure	Specification	Worst margin	Results	Remarks
99% Occupied Bandwidth	IC: RSS-Gen 4.6.1	IC: RSS-Gen 4.6.1	N/A	-	Conducted

Other than above, no addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Radiated emission						
	(3m*)(+dB)				(1m*)(+dB)		(0.5m*)(+dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	4.0dB	5.1dB	5.0dB	5.1dB	6.0dB	4.9dB	4.3dB
No.2	3.9dB	5.2dB	5.0dB	4.9dB	5.9dB	4.7dB	4.2dB
No.3	4.3dB	5.1dB	5.2dB	5.2dB	6.0dB	4.8dB	4.2dB
No.4	4.6dB	5.2dB	5.0dB	5.2dB	6.0dB	5.7dB	4.2dB

*3m/1m/0.5m = Measurement distance

Power meter (+dB)	
Below 1GHz	Above 1GHz
0.7dB	1.5dB

Antenna terminal conducted emission and Power density (+dB)			Antenna terminal conducted emission (+dB)		Channel power (+dB)
Below 1GHz	1GHz-3GHz	3GHz-18GHz	18GHz-26.5GHz	26.5GHz-40GHz	
1.5dB	1.7dB	2.8dB	2.8dB	2.9dB	2.6dB

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

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3.5 Test Location

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	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.0 x 4.5 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.6 x 2.8m	2.4 x 2.4m	-
No.11 measurement room	-	-	6.2 x 4.7 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Data of EMI, Test instruments, and Test set up

Refer to APPENDIX.

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SECTION 4: Operation of E.U.T. during testing

4.1 Operating Mode(s)

Bluetooth (BT): Transmitting (Tx), Payload: PRBS9

Details of Operating Mode(s)

Test Item	Mode	Tested frequency
Spurious Emission (Conducted/Radiated), 20dB Bandwidth, Maximum Peak Output Power	Tx (Hopping off) DH5	2402MHz 2441MHz 2480MHz
Carrier Frequency Separation	Tx (Hopping on) DH5	2402MHz 2441MHz 2480MHz
Number of Hopping Frequency	Tx (Hopping on) DH5	-
Dwell time	Tx (Hopping on), -DH1, DH3, DH5	-
Band Edge Compliance (Conducted)	Tx DH5 -Hopping on -Hopping off	2402MHz 2480MHz
99% Occupied Bandwidth	Tx DH5 -Hopping on -Hopping off	2402MHz 2441MHz 2480MHz
<p>*As a result of preliminary test, the formal test was performed with the above modes, which had the maximum payload length (except Dwell time test)</p> <p>*EUT has the power settings by the software as follows; Power settings: 58 Software: Airoha AB1100 Family LAB Test Tool-Version 1.4.1.0</p> <p>*This setting of software is the worst case. Any conditions under the normal use do not exceed the condition of setting. In addition, end users cannot change the settings of the output power of the product.</p>		

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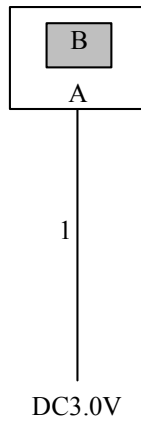
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4.2 Configuration and peripherals



* Cabling and setup(s) were taken into consideration and test data was taken under worse case conditions.

Description of EUT

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	3D active glasses	AN-3DG40	2	Hosiden Corporation	-
B	Bluetooth module	ARC0557	1 for AT 4 for RE	Hosiden Corporation	EUT

RE: Radiated Spurious Emission test
AT: Antenna Terminal Conducted tests

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	DC Cable	2.0	Unshielded	Unshielded	-

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SECTION 5: Radiated Spurious Emission

Test Procedure

EUT was placed on a urethane platform of nominal size, 0.5m by 1.0m, raised 0.8m above the conducting ground plane.

The Radiated Electric Field Strength has been measured in a Semi Anechoic Chamber with a ground plane.

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field strength.

The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.

The measurements were made with the following detector function of the test receiver and the Spectrum analyzer (in linear mode).

The test was made with the detector (RBW/VBW) in the following table.

When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

Test Antennas are used as below;

Frequency	30MHz to 300MHz	300MHz to 1GHz	Above 1GHz
Antenna Type	Biconical	Logperiodic	Horn

In any 100kHz bandwidth outside the restricted band in which the spread spectrum intentional radiator is operating, the radio frequency power that is produced by the intentional radiator confirmed 20dB below that in the 100kHz bandwidth within the band that contains the highest level of the desired power, based on a radiated measurement.

20dBc was applied to the frequency over the limit of FCC 15.209 / Table 5 of RSS-Gen 7.2.5 (IC) and outside the restricted band of FCC15.205 / Table 3 of RSS-Gen 7.2.2 (IC).

Frequency	Below 1GHz	Above 1GHz		20dBc
Instrument used	Test Receiver	Spectrum Analyzer		Spectrum Analyzer
Detector	QP	PK	AV	PK
IF Bandwidth	BW 120kHz(T/R)	RBW: 1MHz VBW: 3MHz	RBW: 1MHz VBW: 10Hz *1)	RBW: 100kHz VBW: 300kHz (S/A)
Test Distance	3m	3m (below 10GHz), 1m*2) (above 10GHz)		3m (below 10GHz), 1m*2) (above 10GHz)

*1) Although 00-705 accepts VBW=10Hz for AV measurements, it was confirmed that superfluous smoothing was not performed.

*2) Distance Factor: $20 \times \log(3.0\text{m}/1.0\text{m}) = 9.5\text{dB}$

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT to see the position of maximum noise, and the test was made at the position that has the maximum noise.

The test results and limit are rounded off to one decimal place, so some differences might be observed.

Measurement range : 30M-25GHz

Test data : APPENDIX

Test result : Pass

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SECTION 6: Antenna Terminal Conducted Tests

Test Procedure

The tests were made with below setting connected to the antenna port.

Test	Span	RBW	VBW	Sweep time	Detector	Trace	Instrument used
20dB Bandwidth	3MHz	30kHz	100kHz	Auto	Peak	Max Hold	Spectrum Analyzer
99% Occupied Bandwidth	Enough width to display 20dB Bandwidth	1 to 3% of Span	Three times of RBW	Auto	Peak	Max Hold *1)	Spectrum Analyzer
Maximum Peak Output Power	-	-	-	Auto	Peak	-	Power Meter (Sensor: 50MHz BW)
Carrier Frequency Separation	3MHz	30kHz	100kHz	Auto	Peak	Max Hold	Spectrum Analyzer
Number of Hopping Frequency	30MHz	300kHz	1MHz	Auto	Peak	Max Hold	Spectrum Analyzer
Dwell Time	Zero Span	100kHz, 1MHz	300kHz, 3MHz	As necessary capture the entire dwell time per hopping channel	Peak	Max Hold	Spectrum Analyzer
Conducted Spurious Emission *2)	9kHz to 150kHz	200Hz	620Hz	Auto	Peak	Max Hold	Spectrum Analyzer
	150kHz to 30MHz	9.1kHz	27kHz				
	30MHz to 25GHz (Less or equal to 5GHz)	100kHz	300kHz				
Conducted Spurious Emission Band Edge compliance	10MHz	100kHz	300kHz	Auto	Peak	Max Hold	Spectrum Analyzer

*1) The measurement was performed with Max Hold since the duty cycle was not 100%.
*2) In the frequency range below 30MHz, RBW was narrowed to separate the noise contents.
Then, wide-band noise near the limit was checked separately, however the noise was low enough as shown in the chart. (9kHz-150kHz:RBW=200Hz, 150kHz-30MHz:RBW=9.1kHz).

The test results and limit are rounded off to two decimals place, so some differences might be observed.

Test data : APPENDIX
Test result : Pass

APPENDIX 1: Data of EMI test

20dB Bandwidth and Carrier Frequency Separation

Test place Head Office EMC Lab. No.11 Measurement Room
Report No. 10105410H
Date 11/23/2013
Temperature/ Humidity 25 deg. C / 54% RH
Engineer Takumi Shimada
Mode Tx (Hopping on) DH5

Mode	Freq. [MHz]	20dB Bandwidth [MHz]	Carrier Frequency Separation [MHz]	Limit for Carrier Frequency separation [MHz]
DH5	2402.0	0.941	1.000	≥ 0.627
DH5	2441.0	0.942	1.000	≥ 0.628
DH5	2480.0	0.943	1.000	≥ 0.629

Limit: Two-thirds of 20dB Bandwidth or 25kHz (whichever is greater).

No limit applies to 20dB Bandwidth.

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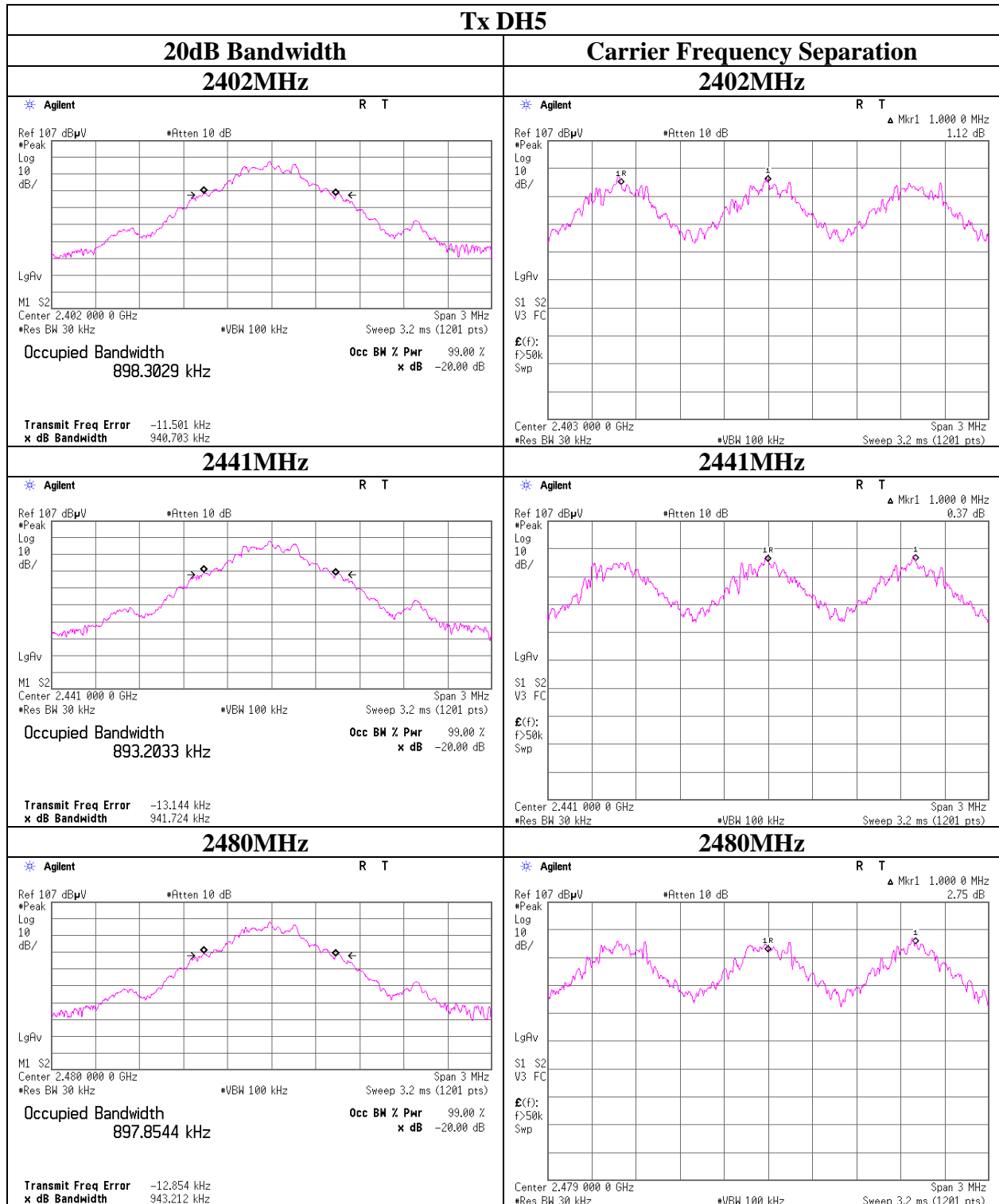
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20dB Bandwidth and Carrier Frequency Separation



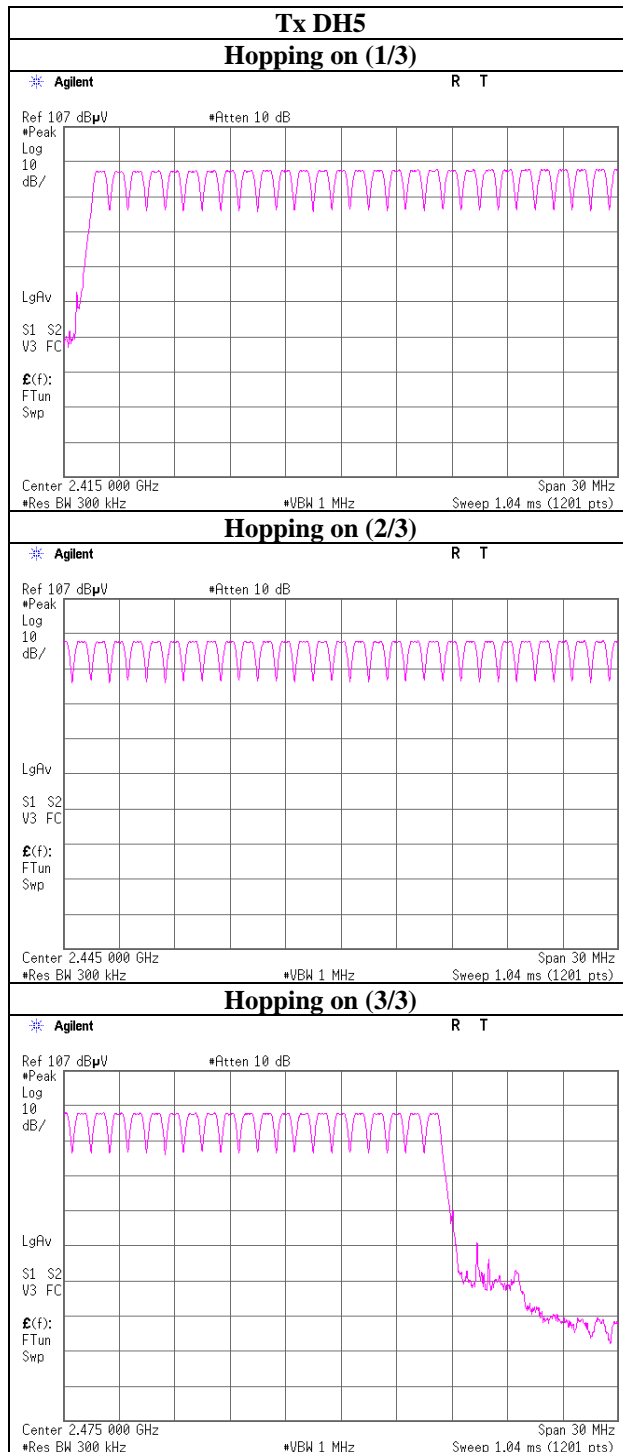
Number of Hopping Frequency

Test place Head Office EMC Lab. No.11 Measurement Room
Report No. 10105410H
Date 11/23/2013
Temperature/ Humidity 25 deg. C / 54% RH
Engineer Takumi Shimada
Mode Tx (Hopping on) DH5

Mode	Number of channel [times]	Limit [times]
DH5	79	>= 15

Test was not performed at AFH mode whose number of hopping channel is 20 channels because this Bluetooth radio is in compliance of Bluetooth Specification.

Number of Hopping Frequency



Dwell time

Test place Head Office EMC Lab. No.11 Measurement Room
Report No. 10105410H
Date 11/23/2013
Temperature/ Humidity 25 deg. C / 54% RH
Engineer Takumi Shimada
Mode Tx (Hopping on) DH5

Mode	Number of transmission in a 31.6(79 Hopping x 0.4) / 12.8(32 Hopping x 0.4)second period			Length of transmission time [msec]	Result [msec]	Limit [msec]
DH1	51.0 times /	5 sec. x	31.6 sec. = 323 times	0.440	142	400
DH3	26.0 times /	5 sec. x	31.6 sec. = 165 times	1.701	281	400
DH5	16.0 times /	5 sec. x	31.6 sec. = 102 times	2.957	302	400

This device complies with the Bluetooth protocol for FHSS operation, employing a pseudo random channel selection and hopping rate to ensure that the occupancy time in $N \times 0.4s$, where N is the number of channels being used in the hopping sequence ($20 \leq N \leq 79$), is always less than $0.4s$ regardless of packet size. This is confirmed in the test report for $N=79$.

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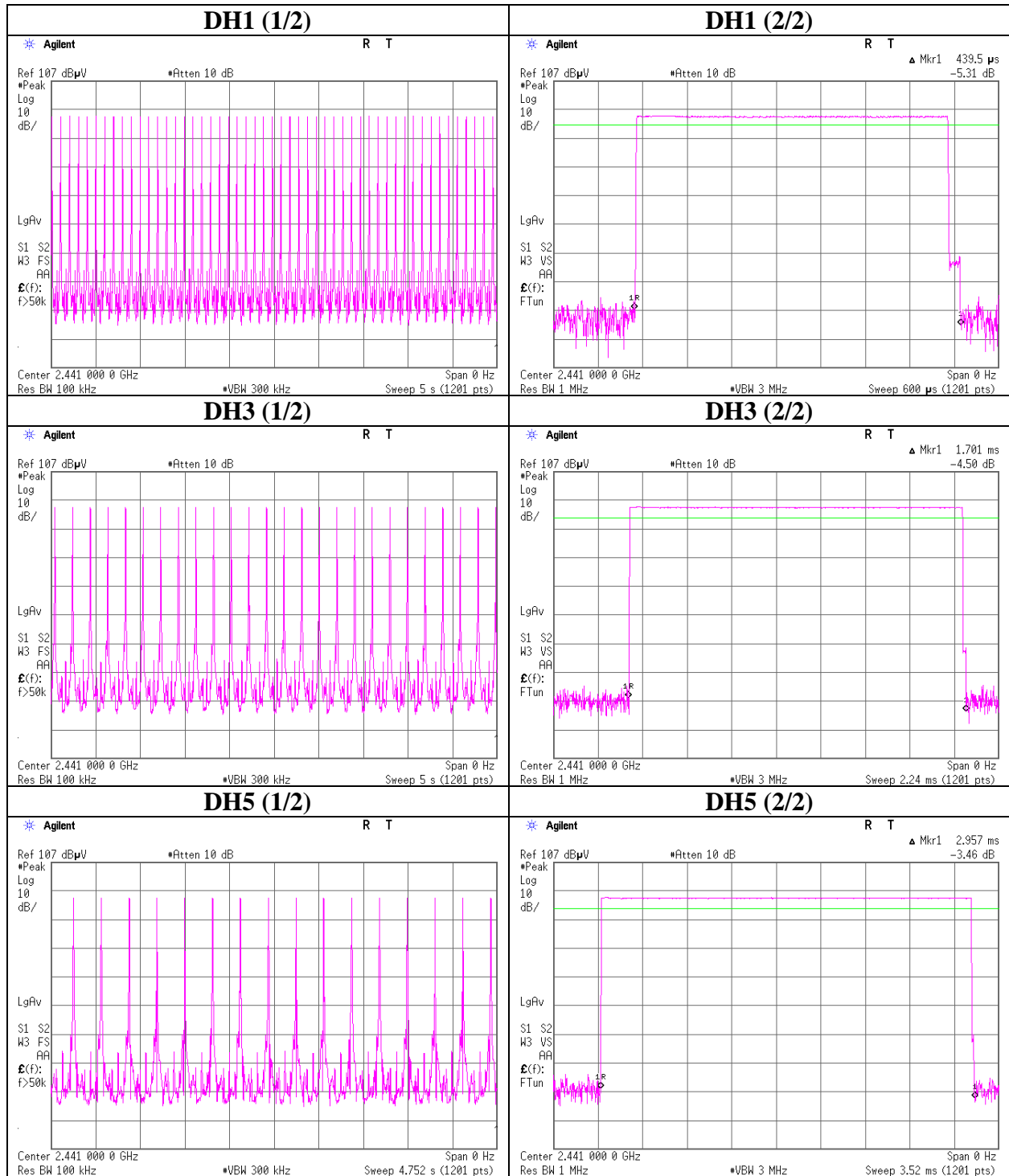
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Dwell time



Maximum Peak Output Power

Test place Head Office EMC Lab. No.11 Measurement Room
Report No. 10105410H
Date 11/23/2013
Temperature/ Humidity 25 deg. C / 54% RH
Engineer Takumi Shimada
Mode Tx (Hopping off) DH5

Mode	Freq. [MHz]	Reading [dBm]	Cable Loss [dB]	Atten. [dB]	Result		Limit		Margin [dB]
					[dBm]	[mW]	[dBm]	[mW]	
DH5	2402.0	-12.58	2.56	9.97	-0.05	0.99	20.96	125	21.01
DH5	2441.0	-12.14	2.57	9.97	0.40	1.10	20.96	125	20.56
DH5	2480.0	-12.17	2.58	9.97	0.38	1.09	20.96	125	20.58

Sample Calculation:

Result = Reading + Cable Loss (including the cable(s) customer supplied)+ Attenuator

Test was not performed at AFH mode, because the decrease of number of channel (min: 20ch) at AFH mode does not influence on the output power and bandwidth of the EUT.
However, the limit level 125mW of AFH mode was used for the test.

Average Output Power (Reference data for SAR testing)

Test place Head Office EMC Lab. No.11 Measurement Room
Report No. 10105410H
Date 11/23/2013
Temperature/ Humidity 25 deg. C / 54% RH
Engineer Takumi Shimada
Mode Tx (Hopping on) DH5

Mode	Freq. [MHz]	Reading [dBm]	Cable Loss [dB]	Atten. [dB]	Result	
					[dBm]	[mW]
DH5	2402.0	-14.11	2.56	9.97	-1.58	0.70
DH5	2441.0	-13.66	2.57	9.97	-1.12	0.77
DH5	2480.0	-13.65	2.58	9.97	-1.10	0.78

Sample Calculation:

Result = Reading + Cable Loss (including the cable(s) customer supplied)+ Attenuator

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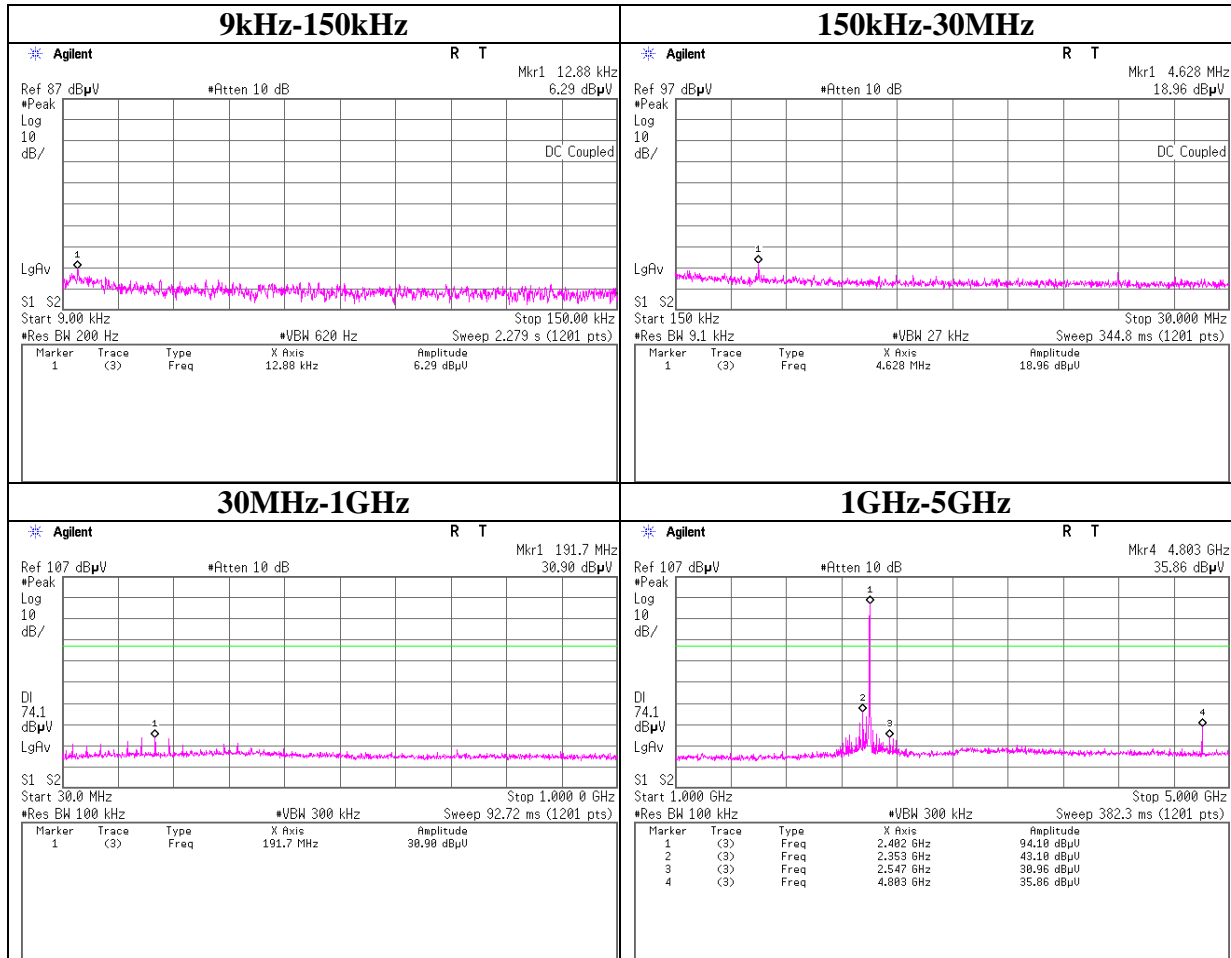
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Conducted Spurious Emission

Tx DH5 2402MHz



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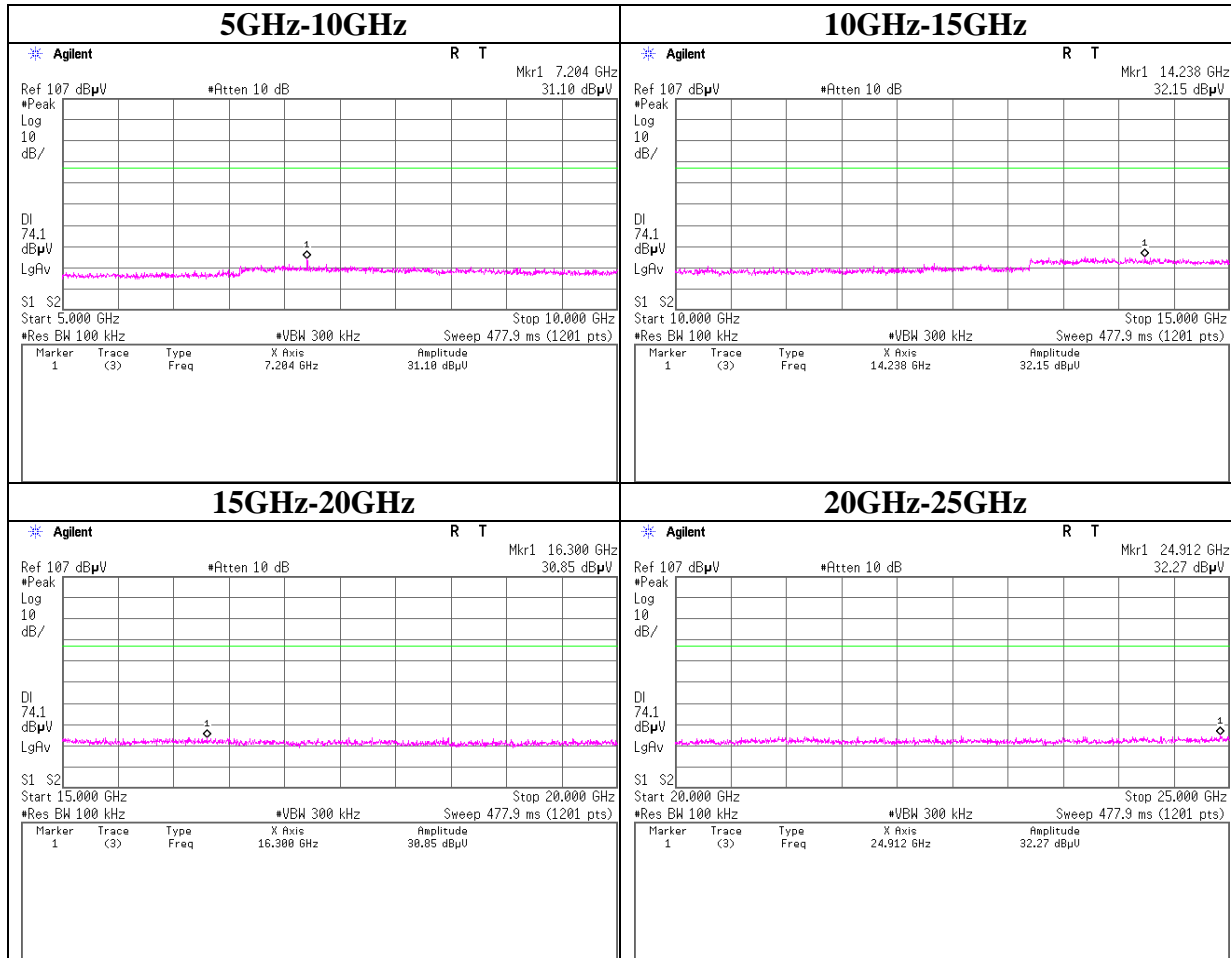
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Conducted Spurious Emission

Tx DH5 2402MHz



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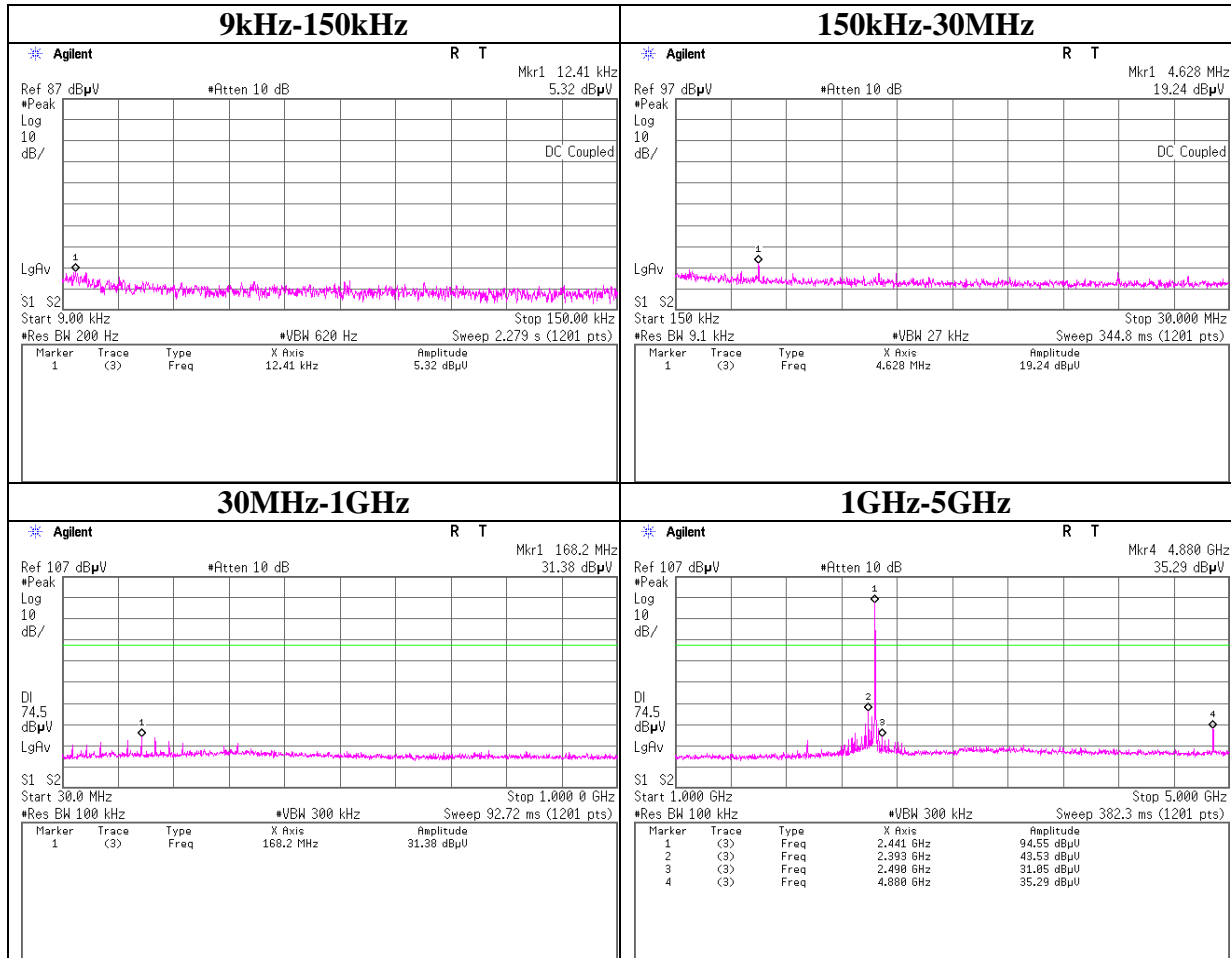
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Conducted Spurious Emission

Tx DH5 2441MHz



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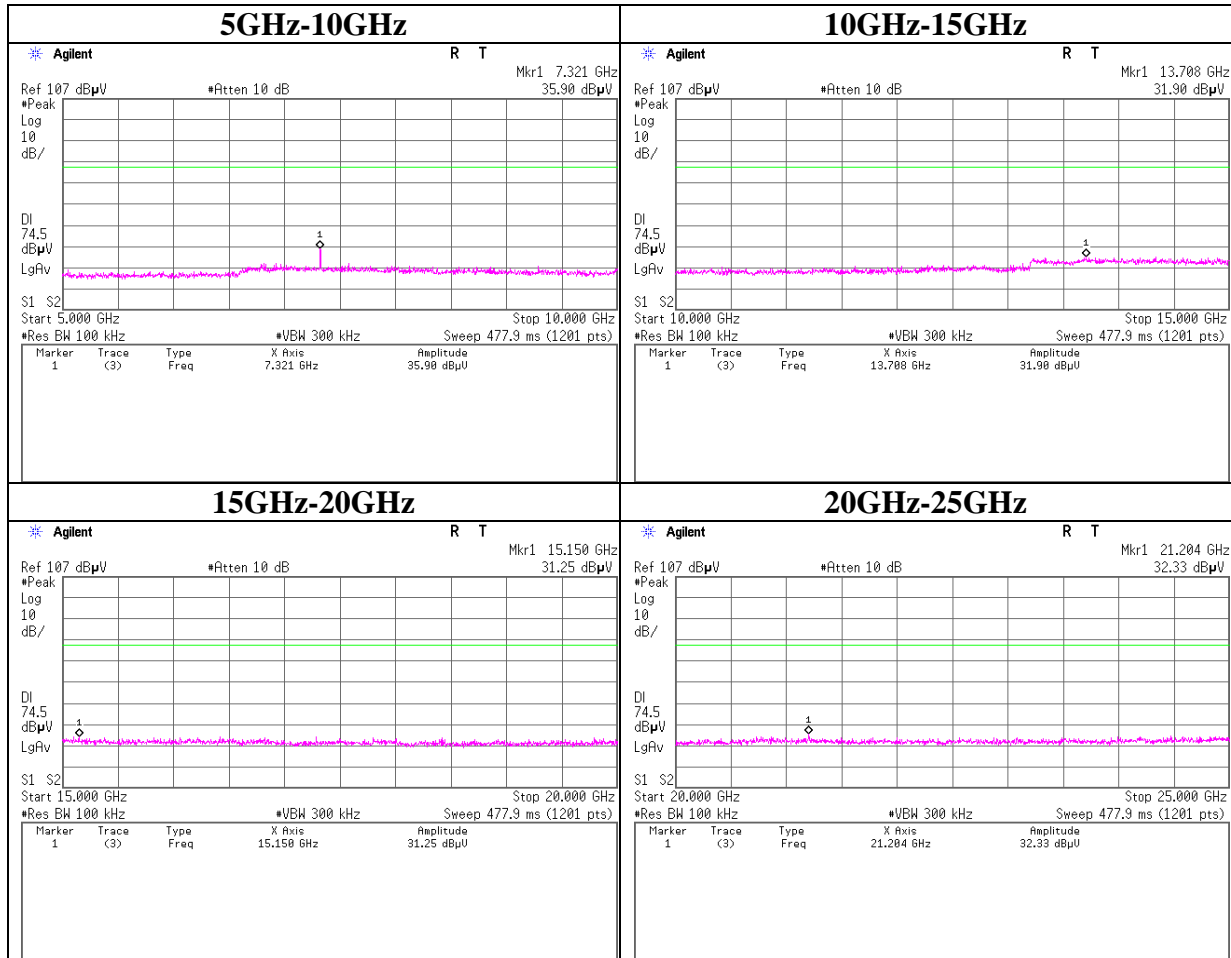
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Conducted Spurious Emission

Tx DH5 2441MHz



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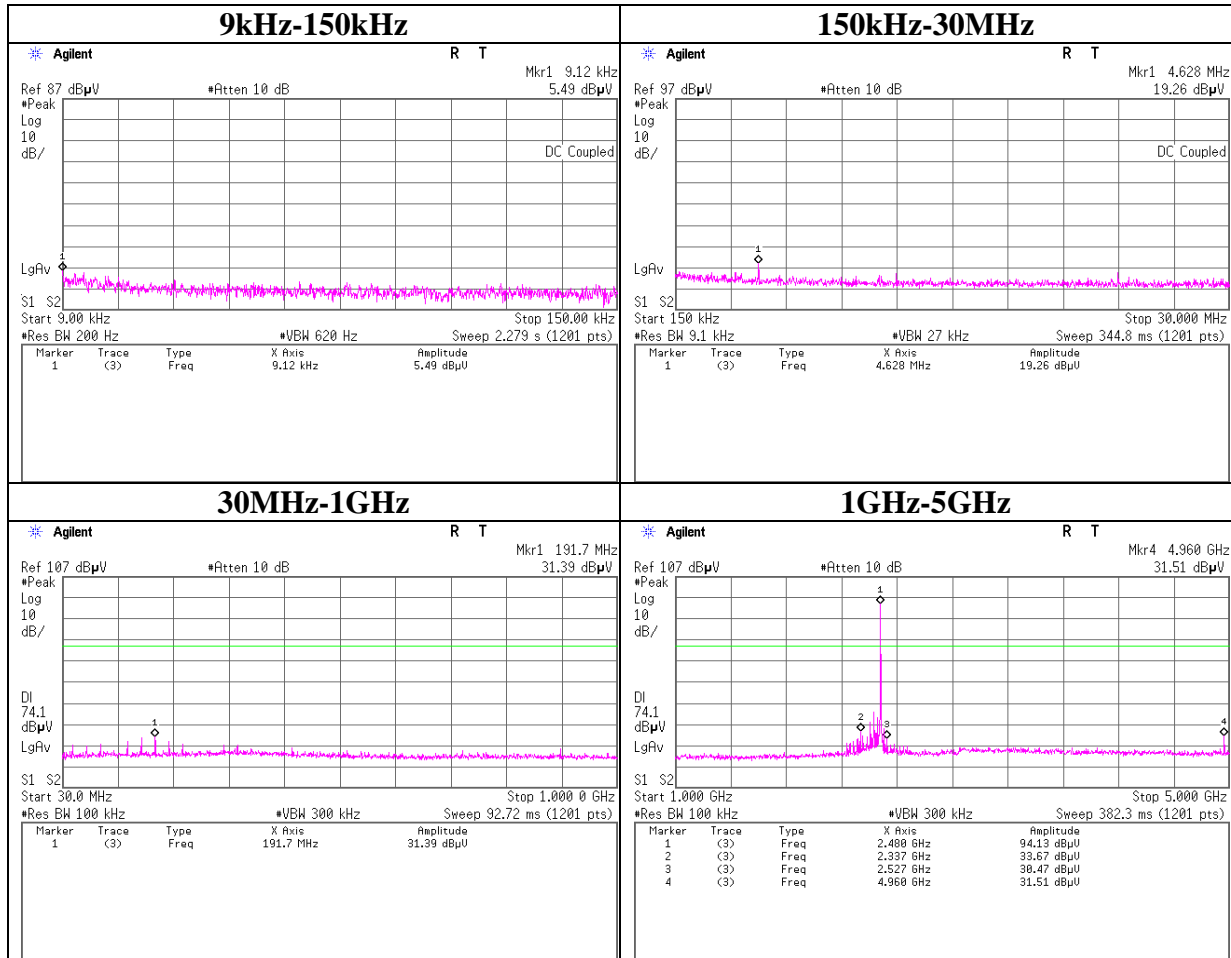
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Conducted Spurious Emission

Tx DH5 2480MHz



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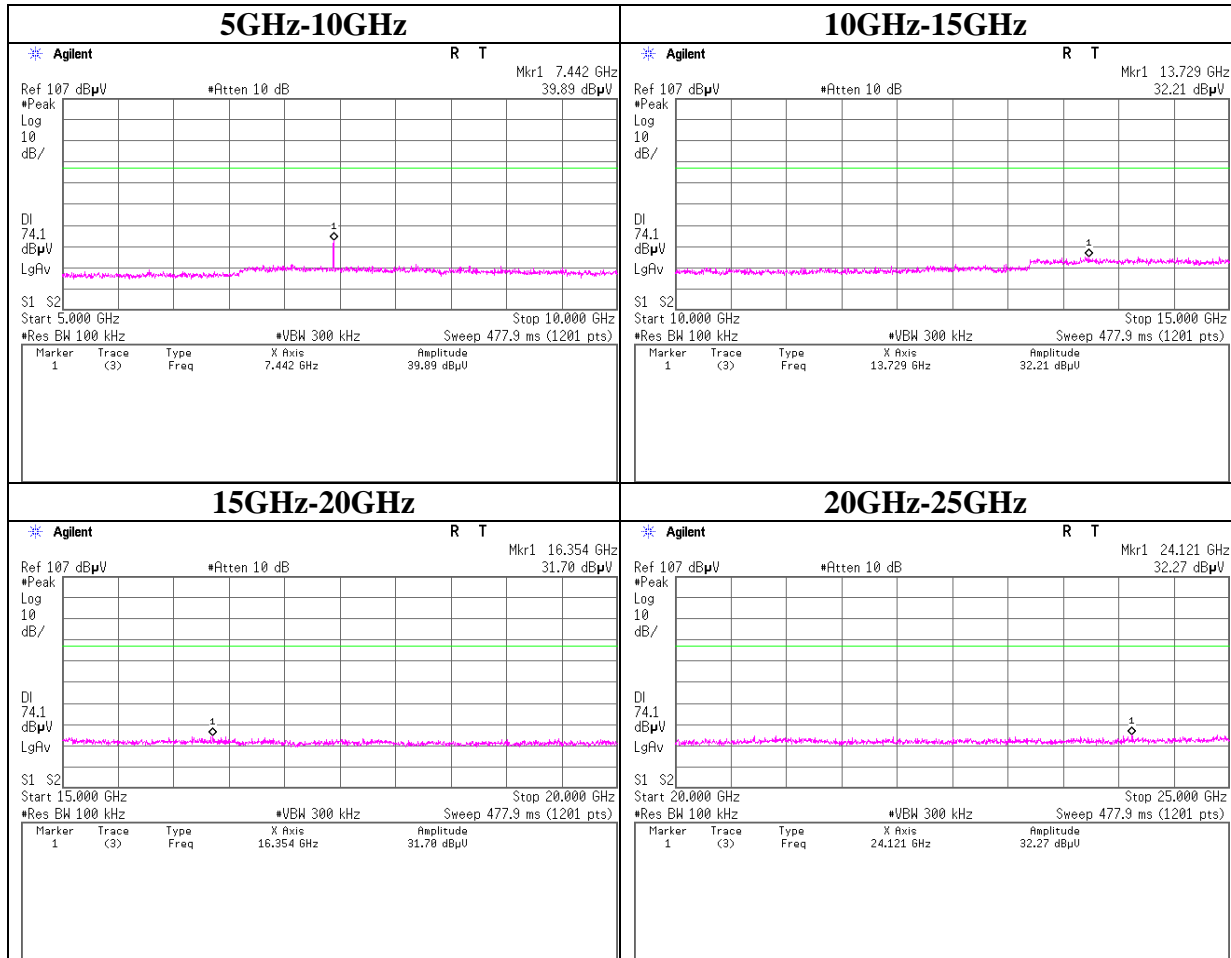
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Conducted Spurious Emission

Tx DH5 2480MHz



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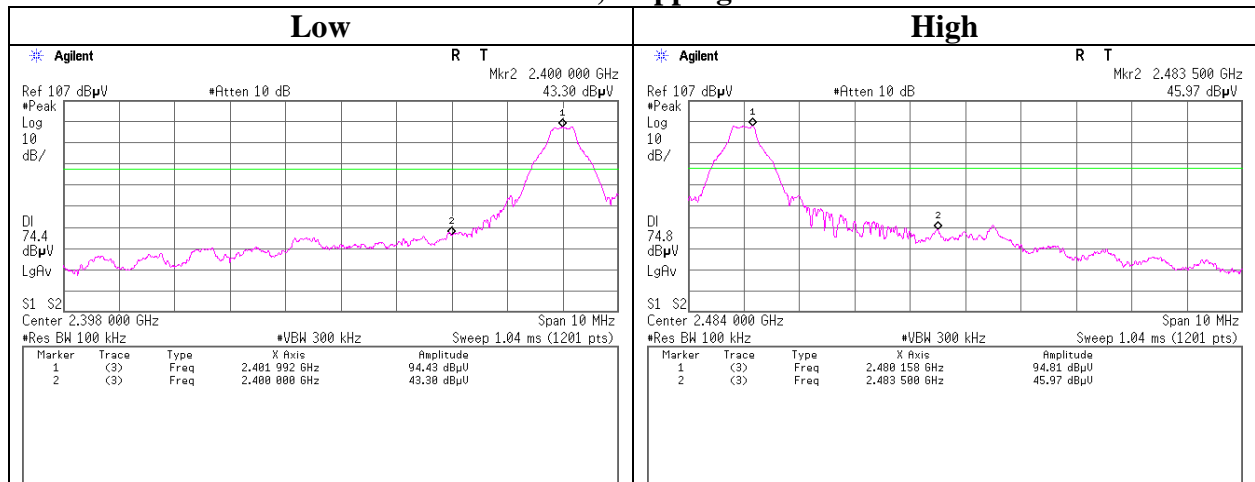
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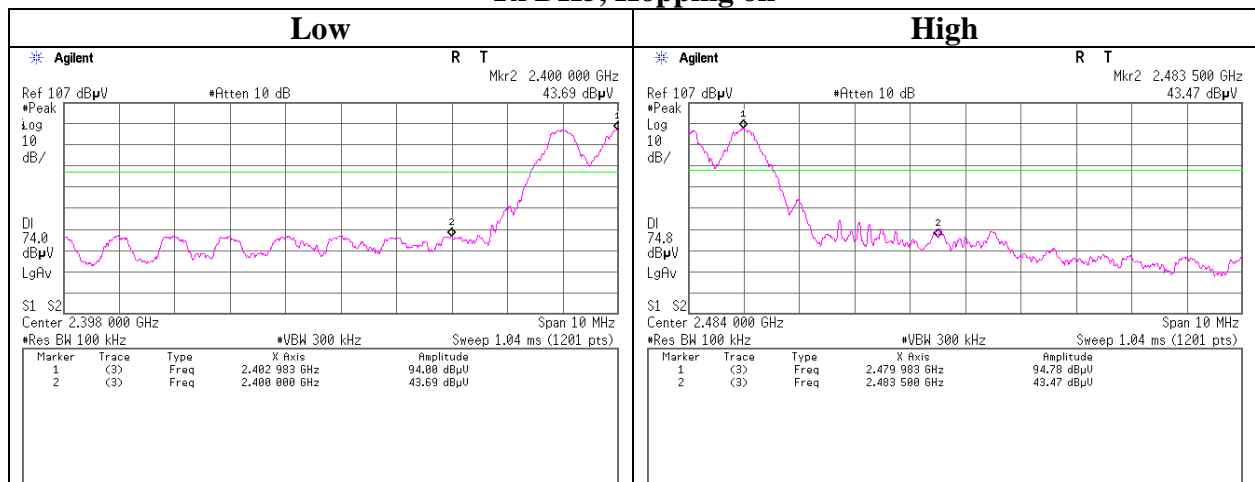
Facsimile : +81 596 24 8124

Conducted Emission Band Edge compliance

Tx DH5, Hopping off



Tx DH5, Hopping on



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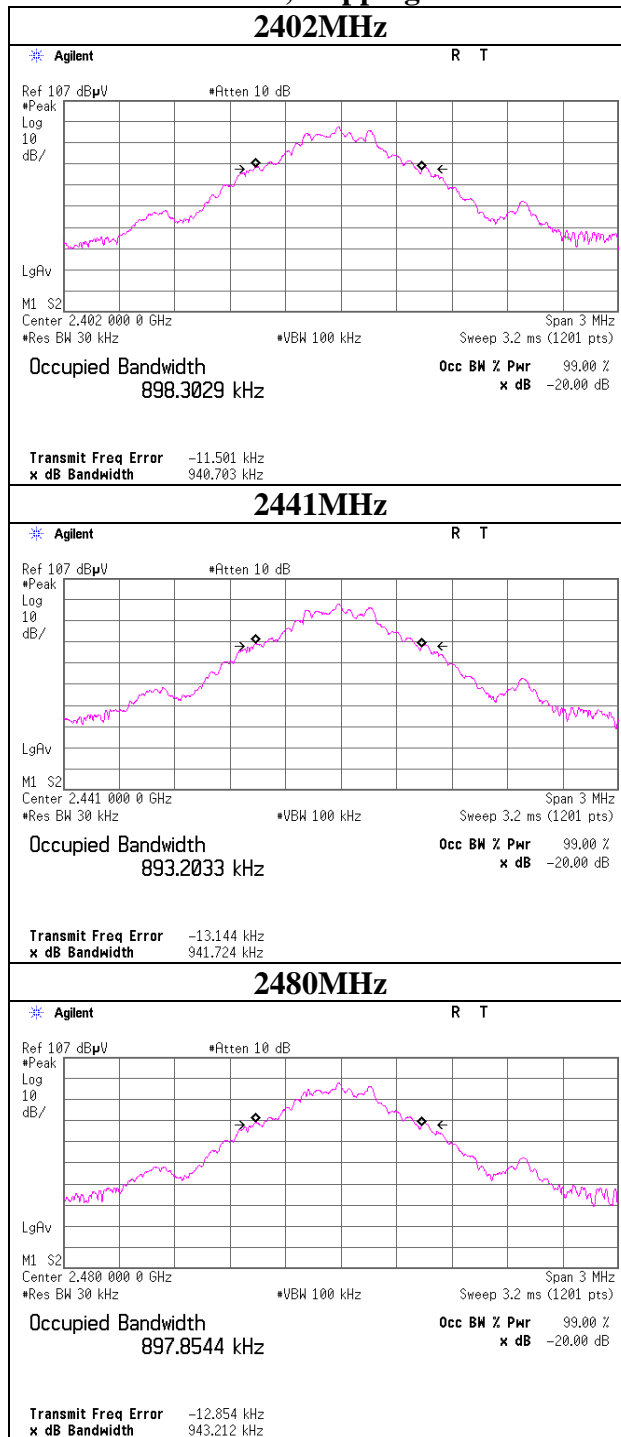
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99% Occupied Bandwidth

Tx DH5, Hopping off



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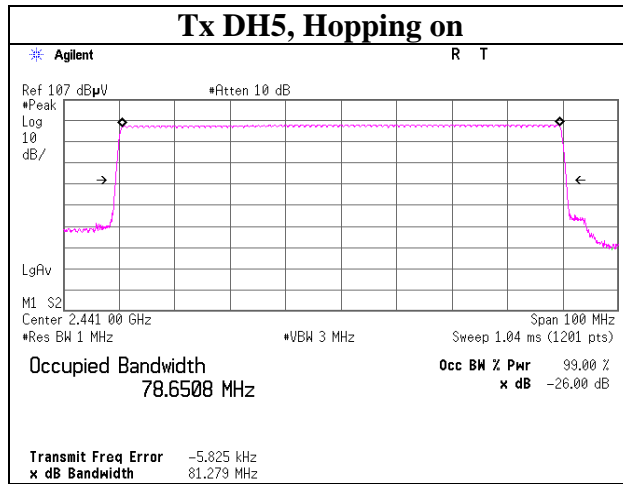
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99% Occupied Bandwidth



APPENDIX 2: Test instruments

EMI test equipment

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-02	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 3m	DA-06902	RE	2013/06/30 * 12
MOS-22	Thermo-Hygrometer	Custom	CTH-201	0003	RE	2013/02/26 * 12
MJM-14	Measure	KOMELON	KMC-36	-	RE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE	-
MSA-03	Spectrum Analyzer	Agilent	E4448A	MY44020357	RE	2013/11/15 * 12
MTR-03	Test Receiver	Rohde & Schwarz	ESCI	100300	RE	2013/06/11 * 12
MBA-02	Biconical Antenna	Schwarzbeck	BBA9106	VHA91032008	RE	2013/10/13 * 12
MLA-02	Logperiodic Antenna	Schwarzbeck	USLP9143	201	RE	2013/10/13 * 12
MCC-12	Coaxial Cable	Fujikura/Agilent	-	-	RE	2013/02/06 * 12
MAT-07	Attenuator(6dB)	Weinschel Corp	2	BK7970	RE	2012/11/06 * 12
MPA-09	Pre Amplifier	Agilent	8447D	2944A10845	RE	2013/09/12 * 12
MRENT-112	Spectrum Analyzer	Agilent	E4440A	MY48250080	RE	2013/10/04 * 12
MHA-06	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	254	RE	2013/02/15 * 12
MPA-10	Pre Amplifier	Agilent	8449B	3008A02142	RE	2013/01/10 * 12
MHA-02	Horn Antenna 18-26.5GHz	EMCO	3160-09	1265	RE	2013/02/15 * 12
MCC-141	Microwave Cable	Junkosha	MWX221	1305S002R(1m) / 1204S062(5m)	RE	2013/05/28 * 12
MHF-06	High Pass Filter 3.5-24GHz	TOKIMEC	TF323DCA	601	RE	2013/05/30 * 12
MPM-09	Power Meter	Anritsu	ML2495A	6K00003348	AT	2013/10/21 * 12
MPSE-12	Power sensor	Anritsu	MA2411B	011598	AT	2013/10/21 * 12
MRENT-112	Spectrum Analyzer	Agilent	E4440A	MY48250080	AT	2013/10/04 * 12
MCC-137	Microwave cable	HUBER+SUHNER	SUCOFLEX 102	37954/2	AT	2013/10/18 * 12
MAT-24	Attenuator(10dB)(above 1GHz)	Agilent	8493C	71389	AT	2013/06/05 * 12
MOS-19	Thermo-Hygrometer	Custom	CTH-201	0001	AT	2012/12/25 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item: RE: Radiated Emission

AT: Antenna Terminal Conducted test

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